

SYSTEM AND METHOD FOR
MEASURING TRANSISTOR LEAKAGE CURRENT
WITH A RING OSCILLATOR WITH BACKBIAS CONTROLS

5 ABSTRACT OF THE DISCLOSURE

A circuit and method thereof for measuring leakage current are described. The circuit includes a pre-charge device subject to a first backbias voltage and a leakage test device subject to a second backbias voltage. The leakage test device is coupled to the pre-charge device. The leakage test
10 device is biased to an off state. A differential amplifier is coupled to the pre-charge device and the leakage test device. A delay unit is coupled to the differential amplifier and to an input of the pre-charge device. The pre-charge device is turned on and off at a frequency that corresponds to said leakage current.

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